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000	340,000			Application Number	09/646,680; Conf. # 5089	
INFORMATION DISCLOSURE				Filing Date	November 4, 2000	
STATEMENT BY APPLICANT			APPLICANT	First Named Inventor	Hideo Yamanaka et al.	
				Art Unit	1762	
	(Use as many sheets as necessary)			Examiner Name	E. B. Fuller	
Sheet	1	of	1	Attorney Docket Number	SON-1782/KOI	

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No.1	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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Examiner Initials*	Cite No.1	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁵ (il known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	ಗ್

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NON PATENT LITERATURE DOCUMENTS						
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